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	:		Applicati it No.	Applicant(s)
•			10/707,639	CO ET AL.
	Notice of A	Allowability	Examiner	Art Unit
· · · · · · · · · · · · · · · · · · ·			Trung Q Nguyen	2829
herewith (or proportion of the NOTICE OF A	ng allowable, PRC reviously mailed), \LLOWABILITY I	ATE of this communication appears SECUTION ON THE MERITS IS a Notice of Allowance (PTOL-85) S NOT A GRANT OF PATENT R the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this a or other appropriate communicate GHTS. This application is subjection	correspondence address application. If not included ion will be mailed in due course. THIS t to withdrawal from issue at the initiative
1. X This co	mmunication is re	esponsive to <u>12/29/03</u> .		
2. X The allo	owed claim(s) is/a	re <u>1-12</u> .		
3. X The dra	awings filed on <u>29</u>	December 2003 are accepted by	the Examiner.	
a) 🔲 /	All b) ☐ Some	de of a claim for foreign priority une* c) □ None of the: ies of the priority documents have		
. 2	2. Certified cop	ies of the priority documents have	been received in Application No.	
3. Copies of the certified copies of the priority documents have been received in this national stage application from the				
International Bureau (PCT Rule 17.2(a)).				
* Certifi	ed copies not rec	eived:		
noted below.	 Failure to timely 	IS FROM THE "MAILING DATE" comply will result in ABANDONM DIS NOT EXTENDABLE.	of this communication to file a rep ENT of this application.	ly complying with the requirements
INFORM	MAL PATENT API	R DECLARATION must be submit PLICATION (PTO-152) which give S (as "replacement sheets",) mus	s reason(s) why the oath or decla	R'S AMENDMENT or NOTICE OF ration is deficient.
(a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached				
		to Paper No./Mail Date		
•		quired by the attached Examiner's	Amendment / Comment or in the	Office action of
	er No./Mail Date			
ldentifying i each sheet.	ndicia such as the Replacement shee	application number (see 37 CFR 1.et(s) should be labeled as such in the	84(c)) should be written on the draw e header according to 37 CFR 1.12	vings in the front (not the back) of 1(d).
7. DEPOS attached	SIT OF and/or IN LExaminer's com	IFORMATION about the deposition of the deposition of the second regarding REQUIREMENT F	it of BIOLOGICAL MATERIAL FOR THE DEPOSIT OF BIOLOGI	must be submitted. Note the CAL MATERIAL.
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Attachment(s) 1 □ Notice of	References Cited	L(PT∩-892)	5 🖂 Notice of Informal	Patent Application (PTO-152)
	•	ent Drawing Review (PTO-948)	•	·
 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 6. ☐ Interview Summary (PTO-413), Paper No./Mail Date <u>0404</u>. 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/08), 7. ☐ Examiner's Amendment/Comment 				ate <u>0404</u> .
Paper No	o./Mail Date	_	<u> </u>	
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Application/Control Number: 10/707,639

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DETAILED ACTION

Allowable Subject Matter

1. Claims 1-12 are allowed.

The following is a statement of reasons for the indication of allowable subject matter: claims 1 and 9 recite, inter alia, "parallel tester comprising a plurality of test drivers for applying test signals to the upper and lower test heads, the test signals for applying test conditions to the memory modules through the pad contactors and the metal pads, each test driver sensing current or voltage conditions on at least one of the metal pads and comparing the current or voltage conditions to predetermined conditions to determine when the memory module has failed; and a positioner that handles the panel and moves the panel into a test position between the upper and lower test heads and removes the panel from the test position after testing by the test driver." In addition, all tests are performed on memory modules before separation from the panel, while the modules are still connected together by the panel links therefore, failing modules can then be marked or noted, and the spacing or pitch of test heads on the tester can be adjusted for different sizes of panels.

The art of record does not disclose the above limitations, nor would it be obvious to modify the art of record so as to include the above limitations. Although Littlebury (U.S. 5,012,187) Method for parallel testing of semiconductor devices and Neeb (U.S. 6,559,673) Apparatus and method for power continuity testing in a parallel testing system, they do not disclose the above-mentioned limitations.

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Conclusion

2. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Trung Nguyen whose telephone number is (571)272-1966. The examiner can normally be reached on Monday through Friday, 8:30AM – 5:00PM. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Cuneo Kamand can be reached at (571)272-1957.

7rung Nguyen
Patent Examiner
Group Art Unit 2829
April 27th, 2004